M easurem ent of the Current-P hase R elation of SFS -Josephson junctions

S.M. Frolov and D.J. Van Harlingen

Departm ent of Physics, University of Illinois at Urbana-Cham paign, Urbana, IL, 61801, USA

V.A.Oboznov, V.V.Bolginov, and V.V.Ryazanov

Institute of Solid State Physics, Russian Academ y of Sciences, Chemogolovka, 142432, Russia

(Dated: March 22, 2024)

We present measurements of the current-phase relation (CPR) of Superconductor-Ferror agnet-Superconductor (SFS) Josephson junctions as a function of temperature. The CPR is determined by incorporating the junction into a superconducting loop coupled to a dc SQUID, allowing measurement of the junction phase di erence. Junctions fabricated with a thin (22 nm) barrier of C $u_{0:47}$ N $i_{0:53}$ sandwiched between Nb electrodes exhibit a re-entrant critical current with temperature, vanishing at T = T 2 4 K. We nd that the critical current is negative for T < T, indicating that the junction is a -Josephson junction. We nd no evidence for second-order Josephson son tunneling near T in the CPR predicted by several theories.

The interplay between superconductivity and magnetism in thin Im Superconductor-Ferrom agnetic (SF) structures has long attracted substantial theoretical and experimental attention. Over twenty years ago, it was predicted that a Superconductor-Ferrom agnet-Superconductor (SFS) Josephson junction could become a -junction, characterized by a m in im um Josephson coupling energy at a phase di erence of , due to exchange eld-induced oscillations of the order parameter (OP) in the ferrom agnetic barrier [1]. Such -junctions were only achieved recently in systems with weak ferrom agnetic barriers and dem onstrated by conventional transport [2, 3, 4, 5, 6] and SQUID interference [7, 8, 9] -Josephson behavior has also been m easurem ents. reported in mesoscopic Superconductor-Normal metal-Superconductor (SNS) junctions driven into a nonequilibrium state by the injection of quasiparticles into the barrier [10, 11], in nanoscale cuprate grain boundary junctions for which the supercurrent is dom inated by zero-energy Andreev bound states induced by the d-w ave order parameter [12], and in nanoscale constrictions in super uid ³He [13]. Because they result in a doublydegenerate phase potential when incorporated into a superconducting loop, -junctions have been proposed as building blocks for superconducting qubits [14].

In this paper, we present m easurements of the currentphase relation (CPR) of an SFS Josephson junction that demonstrate directly the sign change in the critical current when the junction undergoes a crossover into a state below a temperature T at which the critical current vanishes. We investigate the crossover region near T for which it has been predicted that second-order Josephson e ects should dom inate, yielding a sin (2) CPR [15, 16]. We nd no evidence for such a contribution.

A -junction is a Josephson junction with a negative critical current I_c . Thus, the current I_J through a -junction for a given superconducting phase di erence across the junction , assuming a purely sinusoidal form for the CPR, is given by $I_J() = j_L j \sin = 1$

 $j_c j \sin (+)$, in term s of the magnitude of the critical current $j_c j$. The minimum energy state of an isolated -junction corresponds to a phase shift of across the junction [17], in contrast to an ordinary Josephson junction, or 0-junction, for which the minimum energy is at zero phase di erence.

In SF bilayer structures, superconducting correlations are known to exist in the F-layer due to the proxim ity e ect. Because of the exchange eld energy E $_{\rm ex}$, Cooper pairs in the F-layer have non-zero center-of-m assm om entum Q = 2E $_{\rm ex}$ -hv_F, where v_F is the Ferm ivelocity. The wave function of these Cooper pairs at distance x from the SF interface obtains a phase multiplier exp(+ iQ x)



FIG.1: (a) Current vs. voltage for a N b-CuN i-N b Josephson junction measured at T = 1.4 K. (b) Variation of the critical current with temperature showing re-entrance at T 2:7 K characteristic of a transition into a -junction state.

2

or $\exp(iQx)$, depending on the orientation of the electron spins. Taking into account all spin states, the OP

induced in the F-layer, has the form :

(x)
$$\cos \frac{x}{F^2} \exp \frac{x}{F^1}$$
; (1)

which describes the decay of the OP in the ferrom agnetic layer over length $_{F1}$, modulated by spatial oscillations with the period 2 $_{F2}$. In the dirty limit, $_{F1}$ and $_{F2}$ are given by [3]:

$$_{F 1;F 2} = \left(\frac{hD}{\left[(k_{B} T)^{2} + E_{ex}^{2} \right]^{1=2}} \right)_{k_{B}} T ; \quad (2)$$

where D is the di usion constant. Such oscillations of the OP have been con m ed in SF-bilayers by m easurem ents of the superconducting critical tem perature [18] and by tunneling spectroscopy [19].

In SFS junctions, the OP oscillations cause the m agnitude of the critical current to vary with the barrier thickness, vanishing at one or more thicknesses [4, 5, 6]. A ferrom agnetic layer with thickness of order 1/2 (or other odd half-integer value) of the oscillation wavelength results in a sign change in the OP between the superconductor electrodes, meaning that the junction becomes a -junction. Although this condition can be achieved with ultrathin barriers of a strong ferrom agnet [6], it is experim entally advantageous to use thicker barriers of a weakly-ferrom agnetic alloy. Ferrom agnetic layers with thicknesses in the range 10-30 nm are ideal because they are thick enough to form a uniform Josephson barrier yet thin enough to allow a measurable supercurrent. For $_{F1}$ and $_{F2}$ to be in the appropriate range, the Curie tem perature of the ferrom agnetic material should be of order 20 100 K.SFS -junctions of this type have been fabricated using metallic alloys consisting of the strong ferrom agnet N i diluted with either diam agnetic C u [3] or param agnetic Pd [4].

As can be seen from Eq.(2), both $_{F1}$ and $_{F2}$, and hence the junction critical current, vary with temperature. Another advantage of a weak-ferrom agnetic barrier is that E $_{ex}$ can be made comparable to $k_B T$ in the experimentally-accessible temperature range (1 4 K) so that the changes in $_{F1}$ and $_{F2}$ are maximized. This allow s an SFS Josephson junction of appropriate barrier thickness to be tuned between the 0 and states via tem – perature, enabling the crossover region to be explored in a single junction. We utilize this capability in our experiments.

Our SFS junctions were prepared in a multi-step process by optical lithography and magnetron sputtering. The base and top superconducting layers are dcsputtered N b with thicknesses 100 nm and 240 nm respectively, separated by a 22 nm barrier layer of rf-sputtered $C u_{0:47} N i_{0:53}$, a weakly-ferrom agnetic alloy which has a Curie temperature of 60 K. The size of the junctions was 50 m 50 m, as de ned by a window in an insulating SiO layer deposited directly on top of the CuN i.

Because of the low norm al state resistance of the SFS junctions (R_N 10), the current-voltage characteristics of the SFS junctions are measured using a SQUD potention eter setup. In Fig. 1(a), we show a typical I vs. V curve from which the critical current is determ ined. From a series of these curves, the critical current is plotted as a function of tem perature, as in Fig. 1(b). As the tem perature is lowered from 42 K, the critical current decreases, vanishes at a tem perature T = 2.75K, and then increases again. This re-entrance is consistent with a transition between 0-junction and -junction states [3, 5]. At the maximum critical current 10 A, the product $I_c R_N$ 100 pV.

Conventional measurements of the current-voltage characteristic of the junction are not sensitive to the sign of the critical current nor to the shape of the current-phase relation; only $j_c j$ can be determined. To verify -junction behavior, it is necessary to perform a phase sensitive measurement by including the junction in a multiply-connected geometry. The sign of the critical current can be detected in an rf SQUID con guration by shorting the electrodes of the junction with a superconducting loop. For su ciently high inductance L (such that $j_L j = 2$ $j_c j_L = 0$ 1), a loop containing a



FIG.2: (a) C incuit for m easuring the current-phase relations of an SFS junction. (b) M agnetic ux in the rfSQUID loop vs. applied current I showing a transition from hysteretic to non-hysteretic curves as $j_c jdrops$. Curves o set for clarity.

-junction in zero applied magnetic eld will exhibit a spontaneous circulating current, generating a magnetic ux of $(1=2)_{0}$ in the loop which can be detected by a SQUID magnetom eter or Hall probe; for smaller inductance, such that $j_{L} j < 1$, it is energetically favorable to ip the phase of the junction into its high energy state

= 0 in which there is no circulating current. A lternatively, the junction can be connected in parallel with a conventional Josephson junction to form a dc SQUID. In this case, a -junction is idential ed by a minimum of the SQUID critical current in zero magnetic edd. We note that measurements of both the minimum in the critical current in dc corner SQUID s [20] and the spontaneous ux in tricrystal rings [21] have been used to demonstrate a similar but distinct e ect, the phase shift of between orthogonal directions in the d-wave superconducting cuprates.

The m ost complete way to characterize the -junction behavior is to measure the current-phase relation (CPR). The CPR speci es the magnitude and sign of the sinusoidal component of the critical current as well as the amplitudes of any higher harm onics that m ay be present. The CPR can be measured in the rfSQUD con guration shown in Fig. 2(a). A dc SQUD galvanom eter is used to measure the current I_L that ows through the superconducting loop as a function of the current I applied



FIG. 3: Modulation of the magnetic ux in the rf SQUID loop as a function of current applied across the SFS junction for a series of temperatures. As the temperature is lowered, the critical current vanishes at T = 3.59 K, below which the modulation shifts phase by . Curves o set for clarity.

across the junction. The CPR function $I_{\rm J}$ () is related to I and $I_{\rm L}$ by

$$I = I_J () + I_L = I_J \frac{2}{0} + \frac{1}{L};$$
 (3)

where , the totalm agnetic ux in the bop, is related to the junction phase = $2 = _0$ by the phase constraint around the rf-SQUD bop, and to $I_L = =L$ provided that there is no external ux linking the SQUD bop.

For our phase-sensitive measurements, the SFS – junction is incorporated into an rfSQUID loop with inductance L 1 nH. This loop is fabricated in the shape of a planar washer to which a coil of N b superconducting wire is coupled and connected to the input term inals of a commercial dc SQUID sensor. As current I is applied across the SFS junction, the magnetic ux in the loop is modulated due to the winding of the phase of the Josephson junction according to Eq.(3). The inductance L determ ines the critical current range (here up to 300 nA) over which the rfSQUID response remains non-hysteretic (j $_{\rm L}$ j < 1) so that the fullCPR period can be mapped out.

For one sample, a series of curves plotting the ux in the rf-SQUD loop vs. applied current I for dierent tem peratures is shown in Fig. 2(b). We note that the ux axis is self-calibrating since each period corresponds to a one ux quantum 0 change in the loop ux. Plotted in this form, the overall slope of the curves is L, the loop inductance, which is determined to be 128 0:01 nH. The curves are strongly hysteretic at T = 4.2 K and at low tem peratures. They become non-hysteretic in the tem perature range from 3:7 3:5K.AtT 3:6 K, there is no discernible modulation in indicating that $I_c = 0$, and we identify this as the 0 -junction crossover tem perature T . All of the SFS junctions that we have studied were fabricated to exhibit a crossover temperature between 0 and -states in the range 2 4K.

Figure 3 shows in detail the temperature range for



FIG. 4: Current-phase relation derived from the rf $SQ \cup D$ m odulation curves of Fig. 3 showing the transition to a -Josephson junction as the tem perature is low ered.

which 1 1. The modulation of the ux is now L m ore accurately seen to disappear at T = 3.59 K. The most striking feature of the data in Figs. 2 and 3 is that the relative phase of the modulation abruptly changes bv as the tem perature is varied from above to below T. Due to the presence of stray residual magnetic elds 10 m G) in the cryostat, the phase of the modulation ((and hence the junction phase di erence) is not in general zero for zero applied current and varies slightly with tem perature. This background phase shift is roughly linear in the vicinity of the 0 transition.

As can be seen in Eq.(3), the current-phase relation can be directly extracted from the data in Fig. 3 by subtracting the linear ux term and taking account of any phase shifts arising from background elds. The CPR for several tem peratures near T is shown in Fig. 4. The CPR has a sinusoidal form . No doubling of the periodicity is observed in the CPR at any tem perature, suggesting that second-order Josephson tunneling harm onics, if present, never dom inate the CPR of the junction. At T = 3:59 K, only aperiodic uctuations of the current are observed, which lim it the resolution of our critical current m easurem ents to 10 nA. The CPR curves for tem peratures above and below T = 3.59 K are out of phase by , verifying that the critical current of the SFS Josephson junction changes sign at T .

The critical current as a function of temperature can be extracted from the CPR curves, or, more accurately, directly from the family of curves in Fig. 3 by tting them to the form of Eq.(3). For the CPR, we assume the functional form $I_{\rm J}(~)=I_{\rm c}\,\sin(~)+I_{\rm c2}\,\sin(2~),$ allow-ing for a second-order Josephson component. $I_{\rm c}$ and $I_{\rm c2}$ determ ined from the ts are plotted in Fig. 5. The tem – perature variation and sign change of $I_{\rm c}$ are clearly seen. $I_{\rm c2}$ is relatively at, never exceeding a few percent of the maximum sinusoidal component $I_{\rm c}$ and, more significantly, vanishes along with $I_{\rm c}$ at T. This suggests that



FIG. 5: Variation of $I_{\rm c}$ and $I_{\rm c2}$, the sin $% I_{\rm c2}$ and $I_{\rm c2}$, the sin $% I_{\rm c2}$ and sin (2) components of the Josephson critical current, with temperature, showing the sign change in $I_{\rm c}$ and absence of a signi cant $I_{\rm c2}$.

the induced $\rm I_{c2}$ value is likely an artifact of the $~\rm tting$ procedure rather than a physical second-order Josephson component in the CPR .

The sin (2) component has been predicted to persist and dom inate the CPR at the crossover point, inhibiting the critical current from vanishing completely at T [15]. In contrast, our results indicate that the critical current is zero at T and that a sin (2) term is not present in the CPR for these SFS junctions. It should be emphasized that the data presented in this paper is obtained on SFS Josephson junctions in the dirty lim it ' < $_{\rm F\,R}$, where ' is the mean free path in the ferrom agnetic barrier. Som e models predict that the barrier must be in the clean lim it for second-order Josephson tunneling to dom inate the CPR near the 0 transition [16]. In support of this, we note that a $\sin(2)$ component has been observed in voltage-controlled SNS Josephson junctions in the ballistic regime [22]. Thus, it is possible that a sin (2) term may arise in samples in the clean limit or with higher interface transparency.

In conclusion, we have perform ed phase-sensitive m easurem ents on SFS Josephson junctions that exhibit a transition from a 0-state into a -state at a crossover temperature T . The current-phase relation of the junctions is mapped out as a function of temperature, dem onstrating the vanishing of $I_{\rm c}$ at T and the sign change in the critical current at this temperature. No higher-order harm onics in the CPR are observed for these junctions.

We thank M arco Aprili and A lexander G olubov for useful discussions. W ork supported by the N ational Science Foundation grant EIA-01-21568 and by the U S. C ivilian R esearch and D evelopm ent Foundation (CRDF) grant RP1-2413-CG-02. We also acknow ledge extensive use of the M icrofabrication Facility of the Frederick Seitz M aterials R esearch Laboratory at the University of Illinois at Urbana-Cham paign.

- [1] A. I. Buzdin, L. N. Bulaevskii, and S. Panjukov, JETP Lett. 35, 178 (1982).
- [2] A. V. Veretennikov, V. V. Ryazanov, V. A. Oboznov, A. Y. Rusanov, V. A. Larkin, and J. Aarts, Physica B 284-288, 495 (2000).
- [3] V. V. Ryazanov, V. A. Oboznov, A. Y. Rusanov, A. V. Veretennikov, A. A. Golubov, and J. Aarts, Phys. Rev. Lett. 86, 2427 (2001).
- [4] T.Kontos, M.Aprili, J.Lesueur, F.Genet, B.Stephanidis, and R.Boursier, Phys. Rev. Lett. 89, 173007 (2002).
- [5] H. Sellier, C. Baraduc, F. Le och, and R. Calem czuk, Phys. Rev. B 68, 054531 (2003).
- [6] Y.Blum, A.Tsukemik, M.Karpovski, and A.Palevski, Phys. Rev. Lett. 89, 187004 (2002).
- [7] V. V. Ryazanov, V. A. O boznov, A. V. Veretennikov, and A. Y. Rusanov, Phys. Rev. B. 65, 020501 (R) (2001).
- [8] W. Guichard, M. Aprili, O. Bourgeois, T. Kontos, J. Lesueur, and P. Gandit, Phys. Rev. Lett. 90, 167001

- [9] A. Bauer, J. Bentner, M. Aprili, M. L. D. Rocca, M. Reinwald, W. Wegscheider, and C. Strunk, condmat/0312165 (2003).
- [10] J.J.A.Baselm ans, A.F.M orpurgo, B.J.van W ees, and T.M.K lapwik, Nature 397, 43 (1999).
- [11] J.Huang, F.Pierre, T.T.Heikkila, F.K.W ilhelm, and N.O.Birge, Phys. Rev.B 66, 020507 (2002).
- [12] G. Testa, A. Monaco, E. Esposito, E. Samelli, D.-J. Kang, E. Tarte, S. Mennema, and M. Blamire, condmat/0310727 (2003).
- [13] A. Marchenkov, R. W. Simmonds, S. Backhaus, A.Loshak, J.C.Davis, and R.E.Packard, Phys.Rev. Lett. 83, 3860 (1999).
- [14] L.B. Io e, V.B. Geshkenbein, M.V. Feigelman, A.L. Fauchere, and G.Blatter, Nature 398, 679 (1999).
- [15] N.M.Chtchelkatchev, W.Belzig, Y.Y.Nazarov, and C.Bruder, JETP Lett. 74, 323 (2001).

- [16] Z.Radovic, N.Lazarides, and N.Flytzanis, Phys. Rev. B 68, 014501 (2003).
- [17] L.N.Bulaevskii, V.V.Kuzii, and A.A.Sobyanin, JETP Lett. 25, 290 (1977).
- [18] J.S.Jiang, D.D avidovic, D.H.Reich, and C.L.Chien, Phys. Rev. Lett. 74, 314 (1995).
- [19] T.Kontos, M.Aprili, J.Lesueur, and X.Grison, Phys. Rev.Lett. 86, 304 (2001).
- [20] D.A.Wollman, D.J.Van Harlingen, W.C.Lee, D.M. Ginsberg, and A.J.Leggett, Phys. Rev. Lett. 71, 2134 (1993).
- [21] C.C.Tsuei, J.R.Kittley, C.C.Chi, L.S.Yu-Jahnes, A.Gupta, T.Shaw, J.Z.Sun, and M.B.Ketchen, Phys. Rev.Lett. 73, 593 (1994).
- [22] J.J.A. Baselmans, T.T. Heikkila, B.J. van Wees, and T.M. Klapwijk, Phys. Rev. Lett. 89, 207002 (2002).